

EVALUATION OF XRPD DATA FROM REFLECTION AND TRANSMISSION GEOMETRY INSTRUMENTS WITH MULTILAYER OPTICS

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An empirical study of the performance of capillary sample and reflection geometry diffractometers equipped with at least one parallel beam optical component has been completed. Multiple datasets from approximately 10 different diffraction systems have been evaluated with specific emphasis on line width vs. angle, peak position and d-spacing accuracy for indexing and lattice parameter refinements, and intensity. Rietveld analysis of some of the data using analytical profiles and fundamental parameters profiles will be presented.

The data will be presented before the Task Group brings any recommendations to the Technical Committee for evaluation of data from parallel beam systems. The Task Group Chair anticipates at least one recommendation to be put forward that addresses data submission through the Grant-in-Aid program.